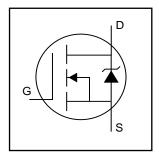
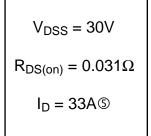
# International TOR Rectifier

# IRFR/U3303

#### HEXFET® Power MOSFET

- Ultra Low On-Resistance
- Surface Mount (IRFR3303)
- Straight Lead (IRFU3033)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated

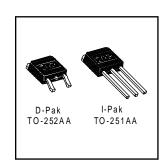




#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for through-hole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.



#### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	33⑤		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	21⑤	A	
I <sub>DM</sub>	Pulsed Drain Current ①	120		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	57	W	
	Linear Derating Factor	0.45	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy②	95	mJ	
I <sub>AR</sub>	Avalanche Current①	18	А	
E <sub>AR</sub>	Repetitive Avalanche Energy ①	5.7	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns	
$T_{\rm J}$	Operating Junction and	-55 to + 150		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )		

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
R <sub>θ</sub> JC	Junction-to-Case		2.2	
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

# IRFR/U3303

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions			
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250\mu A$			
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.032		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA			
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.031	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 18A ④			
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$			
g <sub>fs</sub>	Forward Transconductance	9.3			S	$V_{DS} = 25V, I_D = 18A$			
I	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 30V, V_{GS} = 0V$			
I <sub>DSS</sub>	Diali-10-30dice Leakage Current			250	μΑ	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 150$ °C			
1	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V			
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	11/	V <sub>GS</sub> = -20V			
Qg	Total Gate Charge			29		I <sub>D</sub> = 18A			
Q <sub>gs</sub>	Gate-to-Source Charge			7.3	nC	$V_{DS} = 24V$			
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			13		$V_{GS}$ = 10V, See Fig. 6 and 13 $\oplus$			
t <sub>d(on)</sub>	Turn-On Delay Time		11			$V_{DD} = 15V$			
t <sub>r</sub>	Rise Time		99		ns	$I_D = 18A$			
t <sub>d(off)</sub>	Turn-Off Delay Time		16		115	$R_G = 13\Omega$			
t <sub>f</sub>	Fall Time		28			$R_D = 0.8\Omega$ , See Fig. 10 $\oplus$			
	Internal Drain Inductance		4.5			Between lead,			
L <sub>D</sub>	Internal Drain Inductance		4.5						6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5		nH	from package			
						and center of die contact®			
Ciss	Input Capacitance		750			V <sub>GS</sub> = 0V			
C <sub>oss</sub>	Output Capacitance		400		pF	$V_{DS} = 25V$			
C <sub>rss</sub>	Reverse Transfer Capacitance		140			f = 1.0MHz, See Fig. 5			

#### **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions	
Is	Continuous Source Current			00@		MOSFET symbol	
	(Body Diode)		33®	33 <sup>(5)</sup> A	showing the		
I <sub>SM</sub>	Pulsed Source Current			400	400		integral reverse
	(Body Diode) ①		_	120		p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 18A, V <sub>GS</sub> = 0V ④	
t <sub>rr</sub>	Reverse Recovery Time		53	80	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 18A	
Q <sub>rr</sub>	Reverse RecoveryCharge		94	140	nC	di/dt = 100A/µs ④	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ② Starting  $T_J = 25$ °C,  $L = 590\mu H$  $R_G = 25\Omega$ ,  $I_{AS} = 18A$ . (See Figure 12)
- $\begin{tabular}{l} \begin{tabular}{l} \begin{tab$
- ⓐ Pulse width ≤ 300 $\mu$ s; duty cycle ≤ 2%.
- ⑤ Caculated continuous current based on maximum allowable junction temperature; Package limitation current = 20A.
- 6 This is applied for I-PAK, L<sub>S</sub> of D-PAK is measured between lead and center of die contact
- \*\* When mounted on 1" square PCB (FR-4 or G-10 Material).

  For recommended footprint and soldering techniques refer to application note #AN-994

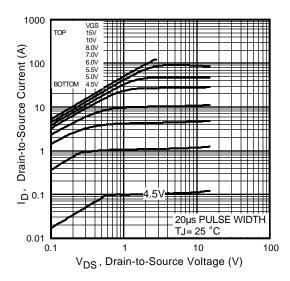
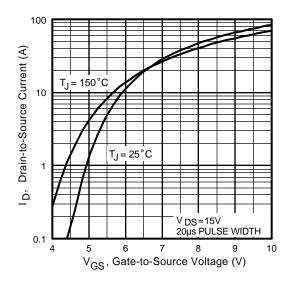


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



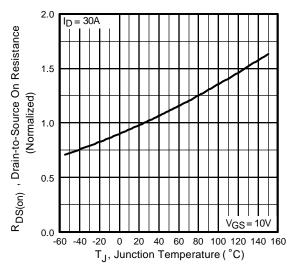
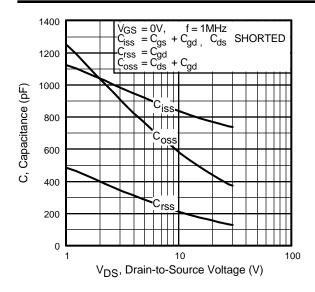


Fig 3. Typical Transfer Characteristics

**Fig 4.** Normalized On-Resistance Vs. Temperature

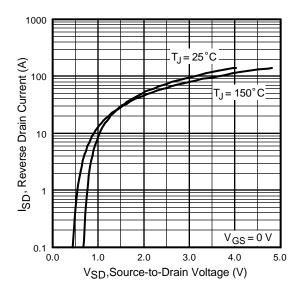


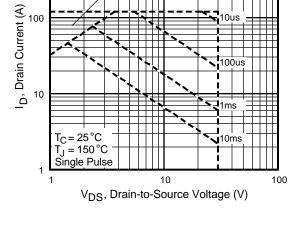
**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

OPERATION IN THIS AREA LIMI BY R<sub>DS(on)</sub>

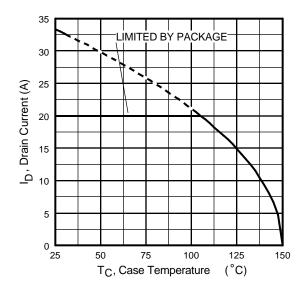
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**Fig 7.** Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

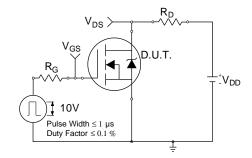


Fig 10a. Switching Time Test Circuit

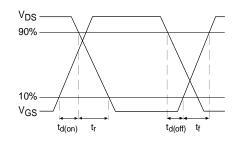


Fig 10b. Switching Time Waveforms

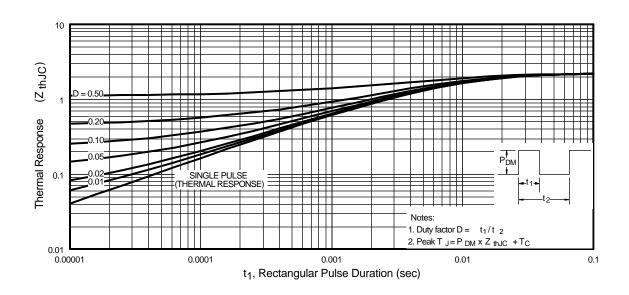


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

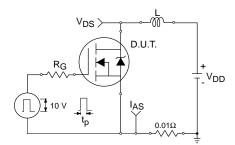


Fig 12a. Unclamped Inductive Test Circuit

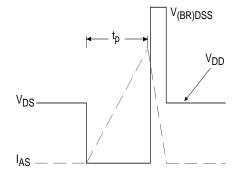


Fig 12b. Unclamped Inductive Waveforms

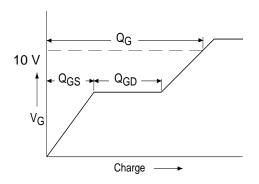
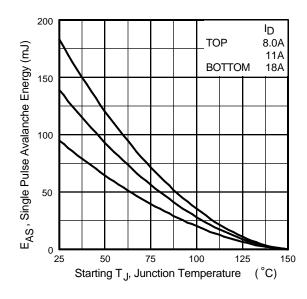


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

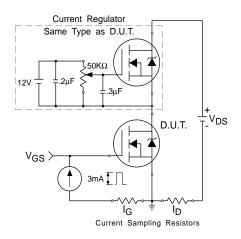
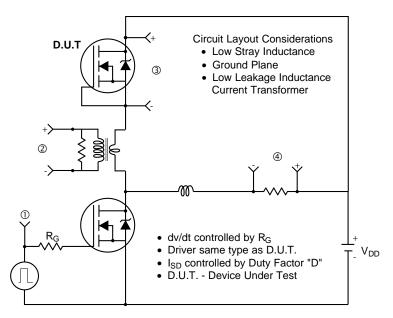
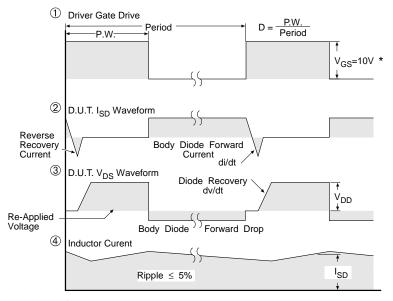


Fig 13b. Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit





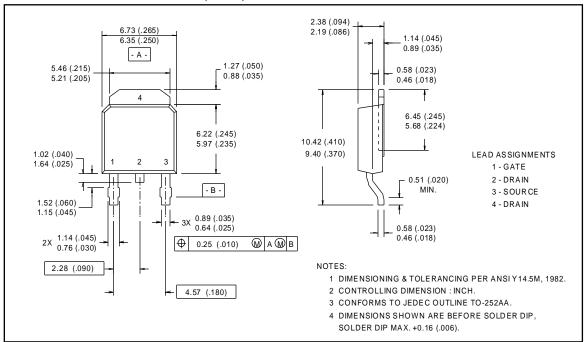
 $^*$  V<sub>GS</sub> = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

## Package Outline

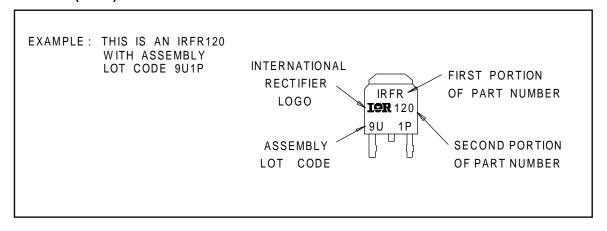
#### **TO-252AA Outline**

Dimensions are shown in millimeters (inches)



# Part Marking Information

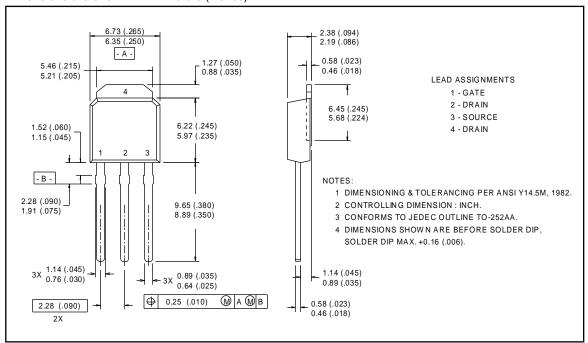
#### TO-252AA (D-Pak)



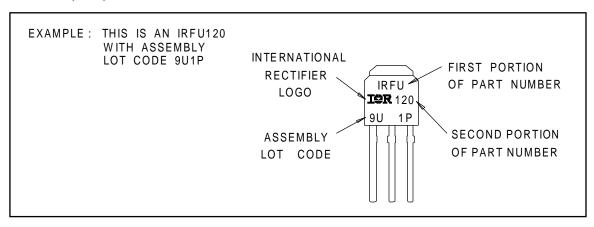
### Package Outline

#### TO-251AA Outline

Dimensions are shown in millimeters (inches)

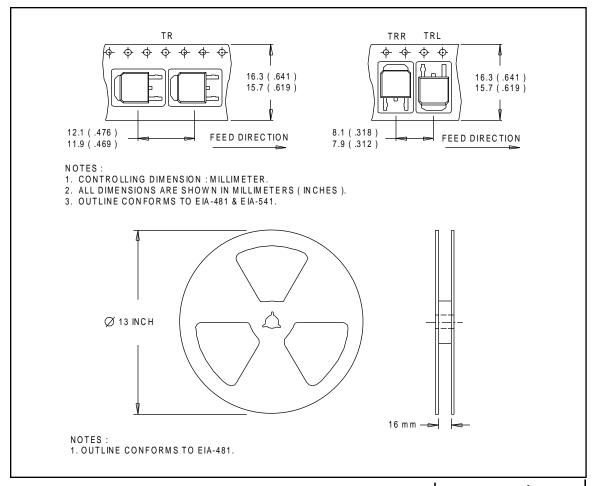


# Part Marking Information TO-251AA (I-Pak)



### **Tape & Reel Information**

#### **TO-252AA**



# International

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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>